

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/815,573	YE ET AL.	
Examiner	Art Unit	
Phallaka Kik	2825	

	SEARCHED				
Class	Subclass	Date	Examiner		
716	4, 21	11/7/2005	PK		
700	97,120	11/7/2005	PK		
700	121	11/7/2005	PK		
430	5	11/7/2005	PK		
378	35	11/7/2005	PK		
382	144,154	11/7/2005	PK		
382	248, 283	11/7/2005	PK		
		×			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
716	4, 21	11/9/2005	PK		
700	97,120	11/9/2005	PK		
700	121	11/9/2005	PK		
430/5; 378/35; 382/144,154,248,283 USPGPUB (see attached)		11/9/2005	PK		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
BRS (EAST)USPAT, USPGPUB CIs/Sub searched: 716/1-21; 700/97,120-121; 430/4-5; 378/34-35 (see attached)	11/7/2005	PK		
BRS (EAST) (Con't)USPAT, USPGPUB Cls/Sub searched: 382/144,154,237,248-250, 280, 283 (see attached)	11/7/2005	PK		
EPO, JPO, IBM TDB, Derwent (see attached)	11/7/2005	РК		
IEE/IEEE Xplore (see attached)	11/7/2005	PK		